

## 100V P-Ch Power MOSFET

### Feature

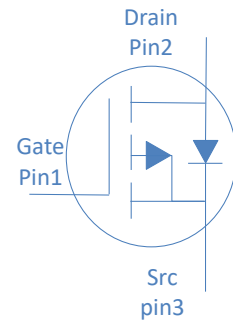
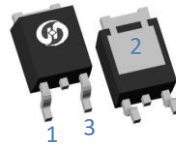
- ◇ High Speed Power Switching, Logic Level
- ◇ Enhanced Avalanche Ruggedness
- ◇ 100% UIS Tested, 100% Rg Tested
- ◇ Lead Free

$V_{DS}$		-100	V
$R_{DS(on),typ}$	$V_{GS}=10V$	63	$m\Omega$
$R_{DS(on),typ}$	$V_{GS}=4.5V$	72	$m\Omega$
$I_D$ (Silicon Limited)		-30	A

### Application

- ◇ Hard Switching and High Speed Circuit
- ◇ DC/DC in Telecoms and Industrial

### TO-252



Part Number	Package	Marking
HTD760P10T	TO-252	TD760P10T

### Absolute Maximum Ratings at $T_J=25^\circ\text{C}$ (unless otherwise specified)

Parameter	Symbol	Conditions	Value	Unit
Continuous Drain Current (Silicon Limited)	$I_D$	$T_C=25^\circ\text{C}$	-30	A
Drain to Source Voltage	$V_{DS}$	-	-100	V
Gate to Source Voltage	$V_{GS}$	-	$\pm 20$	V
Pulsed Drain Current	$I_{DM}$	-	-120	A
Power Dissipation	$P_D$	$T_A=25^\circ\text{C}$	125.0	W
Operating and Storage Temperature	$T_J, T_{stg}$	-	-55 to 150	$^\circ\text{C}$

### Absolute Maximum Ratings

Parameter	Symbol	Max	Unit
Thermal Resistance Junction-Ambient	$R_{\theta JA}$	50	$^\circ\text{C/W}$
Thermal Resistance Junction-Case	$R_{\theta JC}$	1	$^\circ\text{C/W}$

**Electrical Characteristics at  $T_j=25^\circ\text{C}$  (unless otherwise specified)**
**Static Characteristics**

Parameter	Symbol	Conditions	Value			Unit
			min	typ	max	
Drain to Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS}=0V, I_D=-250\mu A$	-100	-	-	V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS}=V_{DS}, I_D=-250\mu A$	-1.0	-	-3.0	
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{GS}=0V, V_{DS}=-100V, T_j=25^\circ\text{C}$	-	-	-25	$\mu A$
Gate to Source Leakage Current	$I_{GSS}$	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	$\pm 100$	nA
Drain to Source on Resistance	$R_{DS(on)}$	$V_{GS}=-10V, I_D=-15A$	-	63	76	m $\Omega$
		$V_{GS}=-4.5V, I_D=-8A$	-	72	92	

**Dynamic Characteristics**

Input Capacitance	$C_{iss}$	$V_{GS}=0V, V_{DS}=-25V, f=1\text{MHz}$	-	2550	-	pF
Output Capacitance	$C_{oss}$		-	345	-	
Reverse Transfer Capacitance	$C_{rss}$		-	70	-	
Total Gate Charge	$Q_g$	$V_{DD}=-80V, I_D=-18A, V_{GS}=-10V$	-	78	101	nC
Gate to Source Charge	$Q_{gs}$		-	8	-	
Gate to Drain (Miller) Charge	$Q_{gd}$		-	20	-	
Turn on Delay Time	$t_{d(on)}$	$V_{DD}=-50V, I_D=-18A, V_{GS}=-10V, R_G=3.3\Omega,$	-	16	32	ns
Rise time	$t_r$		-	7	14	
Turn off Delay Time	$t_{d(off)}$		-	120	240	
Fall Time	$t_f$		-	25	50	

**Reverse Diode Characteristics**

Diode Forward Voltage	$V_{SD}$	$V_{GS}=0V, I_F=-16A$	-		-1.2	V
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Fig 1. Typical Output Characteristics

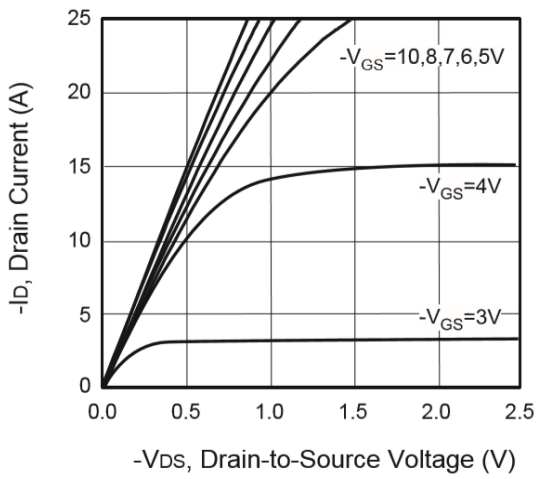


Figure 2. Normalized On-Resistance vs. Junction Temperature

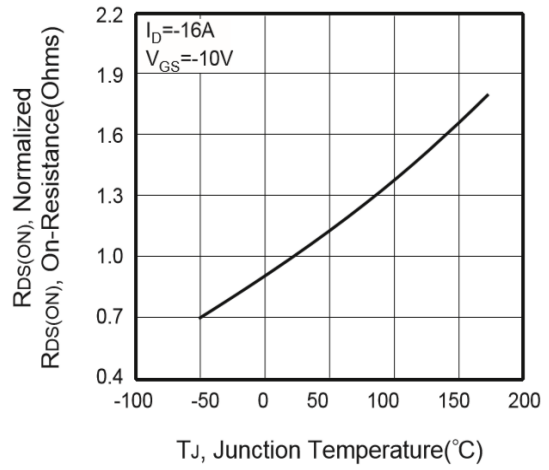


Figure 3. Typical Transfer Characteristics

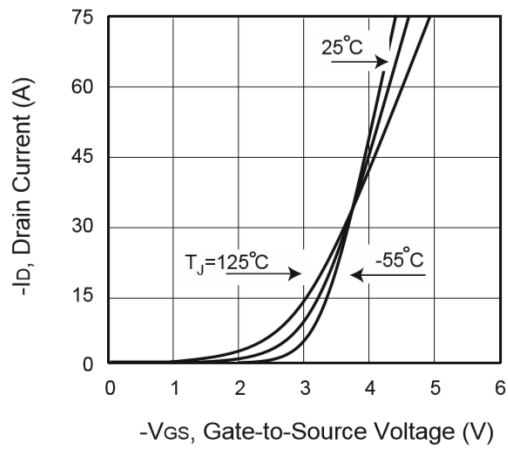


Figure 4. Typical Source-Drain Diode Forward Voltage

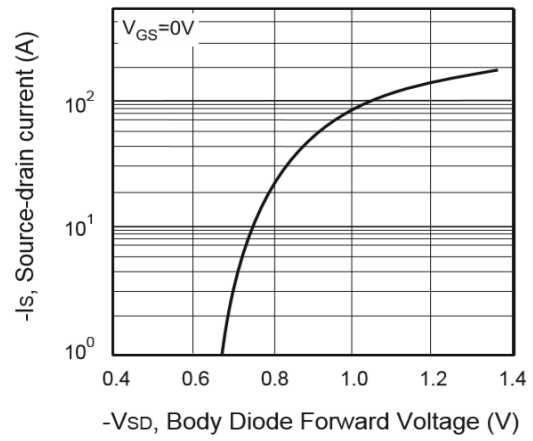


Figure 5. Typical Gate-Charge vs. Gate-to-Source Voltage

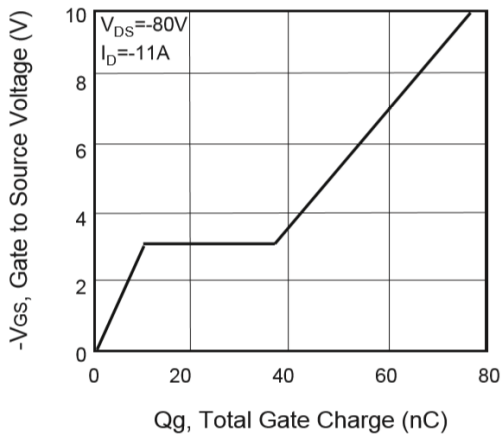


Figure 6. Typical Capacitance vs. Drain-to-Source Voltage

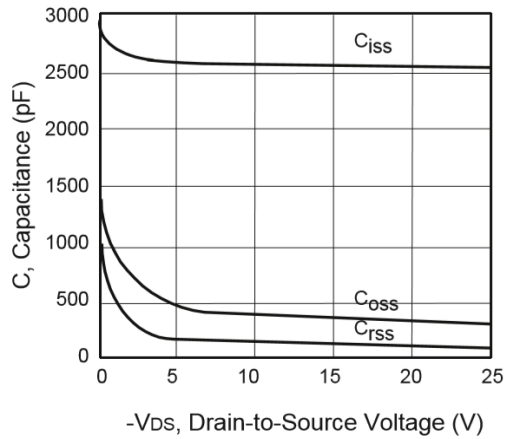


Figure 7. Normalized Gate-Source Threshold Voltage vs temperature

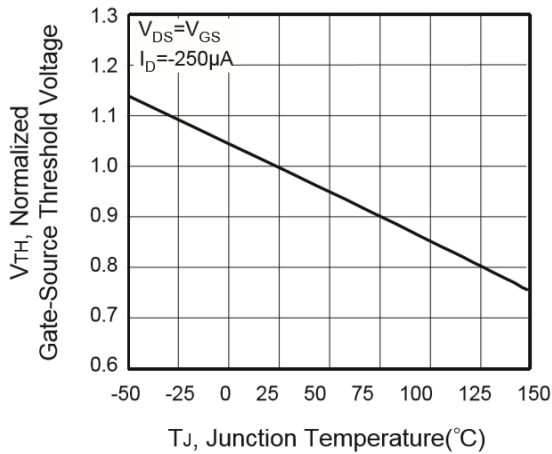


Figure 8. Maximum Safe Operating Area

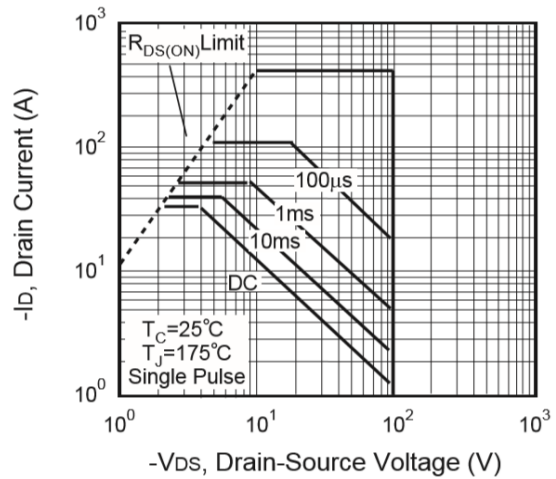
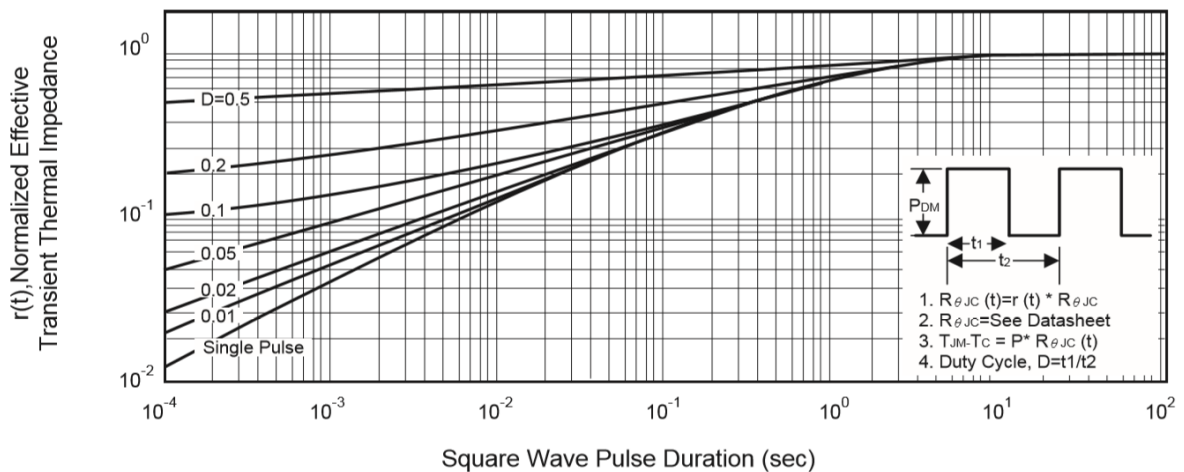
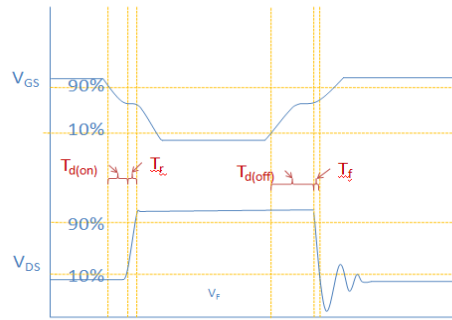
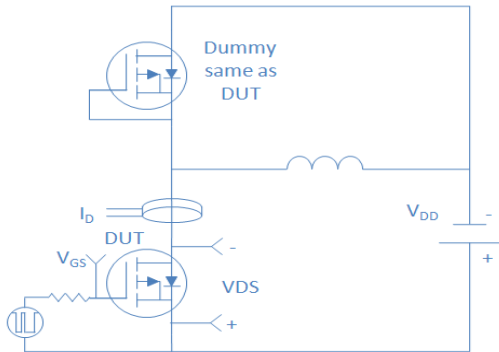


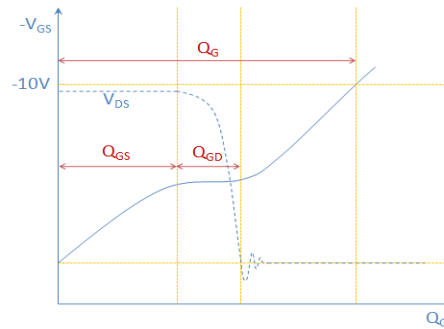
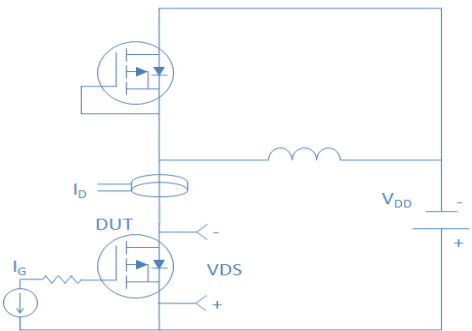
Figure 9. Normalized Maximum Transient Thermal Impedance, Junction-to-Ambient



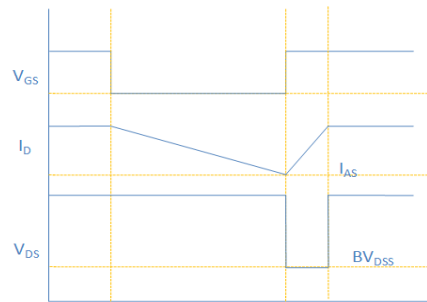
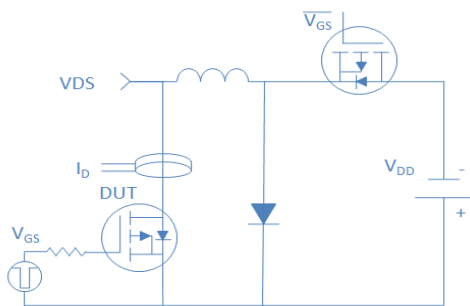
Inductive switching Test



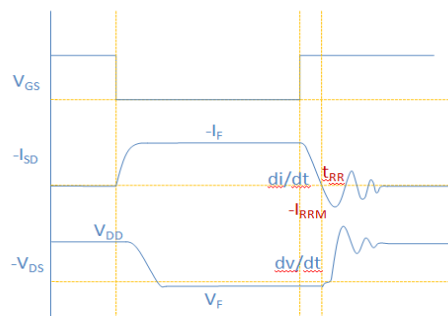
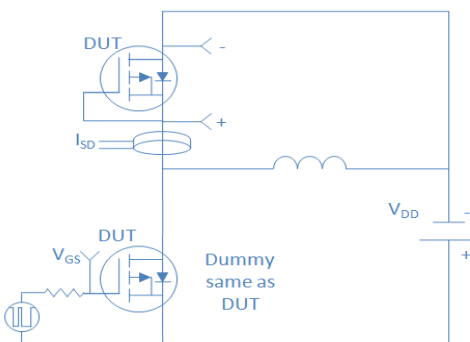
Gate Charge Test

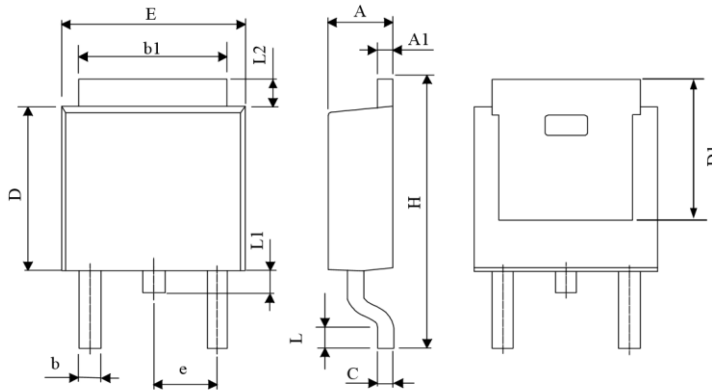


Unclamped Inductive Switching (UIS) Test



Diode Recovery Test



**TO-252, 3 leads**


SYMBOLS	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	2.20	2.40	0.087	0.094
A1	0.45	0.89	0.018	0.035
b	0.50	0.90	0.019	0.035
b1	4.95	5.59	0.195	0.220
C	0.40	0.61	0.016	0.024
D	5.40	6.63	0.213	0.261
E	6.05	7.10	0.238	0.280
e	1.98	2.59	0.078	0.102
H	8.80	10.6	0.346	0.417
L	0.25	--	0.010	--
L1	0.50	1.20	0.020	0.047
L2	0.70	1.78	0.028	0.070
D1	5.00	5.40	0.197	0.213